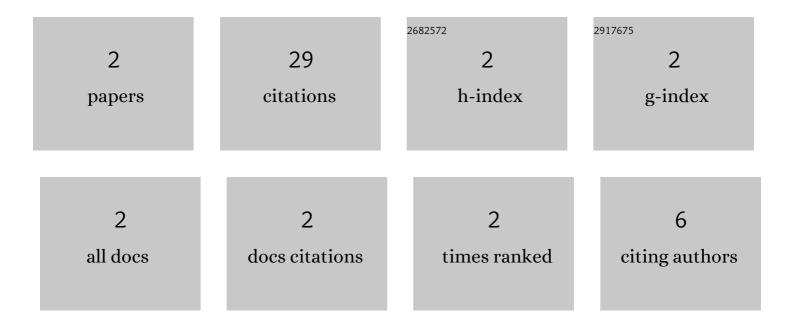
Tao-Ming Chen

List of Publications by Year in descending order

Source: https://exaly.com/author-pdf/9740763/publications.pdf Version: 2024-02-01



#	Article	IF	CITATIONS
1	Integrating content-based image retrieval and deep learning to improve wafer bin map defect patterns classification. Journal of Industrial and Production Engineering, 2022, 39, 614-628.	3.1	6
2	Applying Data Augmentation and Mask R-CNN-Based Instance Segmentation Method for Mixed-Type Wafer Maps Defect Patterns Classification. IEEE Transactions on Semiconductor Manufacturing, 2021, 34, 455-463.	1.7	23

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